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PTO/SB/08A (08-00)

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<b>Substitute for form 1449A/PTO</b>  <b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  (use as many sheets as necessary)		<b>Complete if Known</b>			
		Application Number	10/694,803		
		Filing Date	October 29, 2003		
		First Named Inventor	Shunpei YAMAZAKI et al.		
		Group Art Unit	2823		
		Examiner Name	T. Dang		
Sheet	1	of	2	Attorney Docket Number	0756-7214

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Examiner Initials <sup>2</sup>	Cite No. <sup>1</sup>	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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Examiner Initials <sup>2</sup>	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>2</sup>

Examiner Signature	T. DANG	Date Considered	5/1/06
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Examiner Signature	T. DANG	Date Considered	5/1/06
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